Noisy PAC Learning of Halfspaces

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Plan

 Survey of techniques used in robust PAC learning of halfspaces.

• Recent developments and open problems.

PAC learning of halfspaces

Given measurements $(x, y = sign(w^* \cdot x))$ approximately recover w^* .

• How is *x* generated?

• $x \sim D$, where *D* is an arbitrary distribution over \mathbb{R}^d



PAC learning of halfspaces

Given measurements $(x, y = sign(w^* \cdot x))$ approximately recover w^* .

- What is approximate recovery?
 - Input: $(x_1, y_1), (x_2, y_2,), ... (x_n, y_n)$ generated i.i.d. from D.
 - Output: $h: \mathbb{R}^d \to \{\pm 1\}$ such that $\Pr_{x \sim D}(h(x) \neq sign(w^* \cdot x)) \leq \epsilon$
 - Want runtime poly(n) and $n = \tilde{O}(\frac{d}{\epsilon})$

PAC learning of halfspaces

Constraints

$$\begin{array}{ll} (x_1,+) & w \cdot x_1 > 0 \\ (x_2,-) & w \cdot x_2 < 0 \\ \dots & \dots & \dots \end{array}$$

Theorem[VC]
If
$$n = \tilde{O}(\frac{d}{\epsilon})$$
, then w.h.p. $err(w) \le \epsilon$

$$(x_n, +) \qquad \qquad w \cdot x_n > 0$$

Given corrupted measurements $(x, sign(w^* \cdot x))$ approximately recover w^* .

- In each draw
 - $(x, sign(w^* \cdot x))$, where $x \sim D$ w.p. 1η
 - Arbitrary (x, y) w.p. η
 - How much noise $\eta(\epsilon)$ can be tolerated?

- Cannot tolerate $\eta > \frac{\epsilon}{1+\epsilon}$ [Kearns, Li'88]
- Can tolerate $\eta = O(\epsilon)$ (in principle)

Theorem[VC]:
If
$$n = \tilde{O}\left(\frac{d}{\epsilon^2}\right)$$
 and w has $\frac{\epsilon}{2}$ error on data
then w.h.p. $err(w) \le \epsilon$

Minimizing error on noisy data is NP-hard!

- Cannot tolerate $\eta > \frac{\epsilon}{1+\epsilon}$ [Kearns, Li'88]
- Efficiently: Can tolerate $\eta = O(\frac{\epsilon}{d})$

Proof:

Need ~ \$\frac{d}{\epsilon} \log(1/\epsilon)\$ examples to learn in the noise free case.
\$\mathbb{P}(no example is corrupted) = \$(1-\epsilon)\$ \frac{d}{\epsilon} \log(1/\epsilon)\$ \ge poly(\epsilon)\$

Cannot tolerate
$$\eta > \frac{\epsilon}{1+\epsilon}$$
 [Kearns, Li'88
 Efficiently: Can tolerate $\eta = O(\frac{\epsilon}{d})$

[Daniely'16]: Complexity theoretic evidence that can't get $\eta = O(\epsilon)$ in poly time for a general distribution.

Open: Improve to
$$\eta = \frac{\epsilon}{d^{0.99}}$$

PAC learning with malicious noise (D=Uniform Distribution over S_{d-1})

Efficiently: Can tolerate

• $\eta = O(\frac{\epsilon}{\frac{1}{d^4}})$ [KKMS'05] • $\eta = O(\frac{\epsilon^2}{\log(\frac{d}{\epsilon})})$ [KLS'09] • $\eta = O(\epsilon)$ [ABL'14] PAC learning with malicious noise (D=lsotropic log-concave distribution)

• Efficiently: Can tolerate • $\eta = O(\frac{\epsilon^3}{\log^2(\frac{d}{\epsilon})})$ [KLS'09] • $\eta = O(\epsilon)$ [ABL'14]

Rest of the Talk

- Survey of techniques from [KLS'09, ABL'14]
 - Introduce a margin based technique
- Non-malicious noise models
- Recent developments

- Cannot tolerate $\eta > \frac{\epsilon}{1+\epsilon}$ [Kearns, Li'88]
- Can tolerate $\eta = O(\epsilon)$ (in principle)

Theorem[VC]:
If
$$m = \tilde{O}\left(\frac{d}{\epsilon^2}\right)$$
 and w has $\frac{\epsilon}{2}$ error on data
then w.h.p. $err(w) \le \epsilon$

Minimizing error on noisy data is NP-hard!



Candidate Algorithm

- Sample a set S of noisy examples.
- Output *w* of small hinge loss over *S*.

Uniform Distribution over
$$S_{d-1}$$

$$L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$$

 $E[L_{hinge}(w, x, y)]$: Expected hinge loss over clean dist.

 $\tilde{E}[L_{hinge}(w, x, y)]$: Empirical hinge loss over noisy samples.



Uniform Distribution over
$$S_{d-1}$$

 $L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$
With probability $\geq 1 - \delta$,
 $\forall w, |E[L_{hinge}(w, x, y)] - \tilde{E}[L_{hinge}(w, x, y)]| \leq O\left(\frac{1}{\tau}\sqrt{\frac{d + \log(\frac{1}{\delta})}{n}}\right) + \eta(1 + \frac{1}{\tau})$

Uniform Distribution over
$$S_{d-1}$$

$$L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$$

 $\Pr[|w^* \cdot x| \le \tau] \le O(\tau \sqrt{d})$

 $E[L_{hinge}(w^*, x, y)] \le O(\tau \sqrt{d})$



Uniform Distribution over
$$S_{d-1}$$

If w is the minimizer of hinge loss over noisy data, then w.h.p.

$$E[L_{hinge}(w, x, y)] \le O(\tau \sqrt{d} + \epsilon + \eta(1 + \frac{1}{\tau}))$$

Set
$$\tau = \frac{\epsilon}{c\sqrt{d}} \quad \longrightarrow \quad \eta = \frac{\epsilon^2}{\sqrt{d}}$$



Uniform Distribution over
$$S_{d-1}$$

 $L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$
With probability $\geq 1 - \delta$,
 $\forall w, |E[L_{hinge}(w, x, y)] - \tilde{E}[L_{hinge}(w, x, y)]| \leq O\left(\frac{1}{\tau}\sqrt{\frac{d + \log(\frac{1}{\delta})}{n}}\right) + \eta(1 + \frac{1}{\tau})$

[KKMS'05]

- Sample a set S of noisy examples.
- Remove any pair that is too close to each other

• Distance less than
$$\sqrt{2-c\frac{\log n}{d}}$$

Output w of small hinge loss over S.

[KLS'09]

Sample a set S of noisy examples.

• While there exists a direction u such that $\mathbb{E}_{S}[(u, x)^{2}] > \frac{10 \log n}{d}$

• Remove any $x \in S$ such that $(u, x)^2 > \frac{10 \log n}{d}$

Output w of small hinge loss over S.

$$L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$$

With probability $\geq 1 - \delta$,
 $\forall w, |E[L_{hinge}(w, x, y)] - \tilde{E}[L_{hinge}(w, x, y)]| \leq O\left(\frac{1}{\tau}\sqrt{\frac{d + \log(\frac{1}{\delta})}{n}}\right) + \eta(1 + \frac{1}{\tau}) + \eta + \frac{1}{\tau}\sqrt{\frac{\eta \log n}{d}}$

- Sample a set S of noisy examples.
- Iteratively do (Outlier removal + hinge loss minimization).

Idea inspired from the active learning literature.

- Suppose we have w_k, s.t. err(w_k) ≤ γ
 ⇒ θ(w_k, w^{*}) ≤ γπ



W.

νπ

w*



Suppose we have w_k , s.t. $err(w_k) \le \gamma$ ⇒ $\theta(w_k, w^*) \le \gamma \pi$

•
$$\mathbf{w}^* \cdot \mathbf{x} = \mathbf{w}_k \cdot \mathbf{x} + (\mathbf{w}^* - \mathbf{w}_k) \cdot \mathbf{x}$$

 $\leq \nu \pi$



• If $|w_k \cdot x| > \pi \gamma$, then w_k and w^* agree on the label of x.

Find $w \in B(w_k, \gamma \pi)$ of low error w.r.t. $D_{x \in R}$



 W_k • Suppose we have w_k , s.t. $err(w_k) \leq \gamma$ w* • $\Rightarrow \theta(w_k, w^*) \leq \gamma \pi$ Lemma: If $\theta(w, w^*) = \gamma \pi$, $\Pr\left[(w^* \cdot x)(w \cdot x) < 0, |w \cdot x| > \frac{2\pi\gamma}{\sqrt{d}}\right] \le \frac{\gamma\pi}{8}$ R $R = \{x \colon |w_k \cdot x| \le \frac{2\pi\gamma}{\sqrt{d}}\}$

Find
$$w \in B(w_k, \frac{2\gamma\pi}{\sqrt{d}})$$
 of low error w.r.t. $D_{\chi \in R}$

- To improve the error of current w_k from γ to $\frac{\gamma}{2}$, enough to get error O(1) w.r.t. $D_{x \in R}$.
- At each step solve the above subproblem robustly.





Find
$$w \in B(w_k, \frac{2\gamma\pi}{\sqrt{d}})$$
 of low error w.r.t. $D_{x \in R}$
• Noise cannot hurt the hinge loss by a lot:
 $|w \cdot x| \le 2\pi\gamma$.

 $R = \{x \colon |w_k \cdot x| \le \frac{2\pi\gamma}{\sqrt{d}}\}$

w*

R

Find
$$w \in B(w_k, \frac{2\gamma\pi}{\sqrt{d}})$$
 of low error w.r.t. $D_{x \in R}$
• Can do better outlier removal
 $\forall w \in B\left(w_k, \frac{2\gamma\pi}{\sqrt{d}}\right), E_{D_{x \in R}}[(w \cdot x)^2] \leq O(\frac{\gamma^2}{d})$
 $R = \{x : |w_k \cdot x| \leq \frac{2\pi\gamma}{\sqrt{d}}\}$

$$L_{hinge}(w, x, y) = \max\left(0, 1 - \frac{y(w \cdot x)}{\tau}\right)$$

With probability $\geq 1 - \delta$,
 $\forall w, |E[L_{hinge}(w, x, y)] - \tilde{E}[L_{hinge}(w, x, y)]| \leq O\left(\frac{1}{\tau}\sqrt{\frac{d + \log(\frac{1}{\delta})}{n}}\right) + \eta(1 + \frac{1}{\tau}) + \eta + \frac{1}{\tau}\sqrt{\frac{\eta\gamma}{d}}$

Initialize w_1 randomly. Iterate $k = 2,3, ..., log(\frac{1}{\epsilon})$

- Sample m_k examples x satisfying $|w_{k-1} \cdot x| \le \frac{2\pi\gamma_{k-1}}{\sqrt{d}}$
- Need constant error in each round, hence O(d) labeled examples
- Total # labeled examples = $O(dlog(\frac{1}{\epsilon}))$
 - Find w_k in $B(w_{k-1}, 2\pi\gamma_{k-1})$ of small hinge loss.
 - Clear working set S.

end iterate

- $\eta = O(\frac{\epsilon}{d^{\frac{1}{4}}})$ [KKMS'05]
- $\eta = O(\frac{\epsilon^2}{\log(\frac{d}{\epsilon})})$ [KLS'09]
- $\eta = O(\epsilon)$ [ABL'14]
- $\eta = \frac{\epsilon}{2+\delta}$ if only noise in labels [Daniely'15]
 - by combining margin based technique with polynomial regression.
- Extend margin based learning to robustly learn a broader class of distributions [BZ'17].
- Robust learning of non-linear models [DKS'18].



$$p_{x} = P(y \neq sign(w^{*} \cdot x)|x) \le \frac{1}{2} - \beta,$$

$$0 \le \beta \le \frac{1}{2}$$

- Can learn with $O(\frac{d}{\epsilon^2 \beta^2})$ samples in exponential time.
 - Current complexity theoretic reductions do not work in this model.
- [ABHZ'16]: Can learn under isotropic log-concave distributions in polynomial time for any constant β .

Bounded (Massart) Noise

$$p_x = P(y \neq sign(w^* \cdot x)|x) \leq \frac{1}{2} - \beta,$$

$$0 \le \beta \le \frac{1}{2}$$

- [CLZ'17]: Practical algorithms based on SGD.
- [YZ'17, Zhang'18]: Practical algorithms based on (margin + perceptron). Also label efficient.
- Guarantees hold for uniform distribution. Can handle β arbitrarily close to zero.
- Open: fast algorithms for isotropic log-concave distributions?
- Open: polynomial time algorithms for Massart noise beyond log-concave?

$$\forall t > 0, \mathbb{P}_X\left(\left|p_x - \frac{1}{2}\right| < t\right) \le Bt^{\alpha}$$

• Can achieve rates
$$\sim \left(\frac{d \log n + \log(\frac{1}{\delta})}{n}\right)^{\frac{1+\alpha}{2+\alpha}}$$

Open: a polynomial time PAC learning algorithm?

4 1 0

Recap of Open Questions

- PAC learn halfspaces under malicious noise with $\eta = \frac{\epsilon}{d^{0.99}}$?
- Show that SGD based algorithms work for Massart noise beyond the uniform distribution?
- Design polynomial time learning algorithms for Massart noise for a broad class of distributions?
- Design polynomial time algorithm for Tsybakov noise in any nontrivial setting?
- Explore intermediate noise models for PAC learning?

THANK YOU